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BC106N-UV - August 31, 2021

Item # BC106N-UV was discontinued on August 31, 2021 For informational purposes, this is a copy of the website content at that time and is valid only for the stated product.

CCD CAMERA BEAM PROFILER

- 190 350 nm and 350 1100 nm Wavelength Ranges Available
- Beam Diameter: 30 µm 6.6 mm
- For Continuous Wave, Pulsed Beams, and Single Pulses
- M² Measurement with Optional Extension Set



BC106N-UV Filter Wheel with 6 Neutral Density Filters Included Post and Post Holder Sold Separately



Versatile Software Package

Application Idea

Use the BC106N-VIS with the M2MS M2 Extension Set to create a complete beam quality measurement system.



OVERVIEW

Features

- · Full 2D Analysis of Complex Beam Profiles
- For CW or Pulsed Laser Beam and Single Pulse Analysis
- High Resolution: 1360 x 1024 Pixels
- Low Noise: S/N ≥ 62 dB
- 12-Bit CCD Camera
- · Large Sensor Area (8.77 mm x 6.6 mm) for Uniformity and Linearity
- · Removable, AR-Coated, Wedged Window Protects Sensor from Dust
- User-Calibratable Power Readout
- Auto Exposure from 20 µs to 1 s and Gain Control from 1x to 16x
- Black Level and Ambient Light Compensation
- External Shutter Trigger Input
- Optional M² Extension Kit for Automated M² Analysis (See Below)

Thorlabs' Camera-Based Beam Profilers allow complex mode patterns (like flat top and donut) to be identified while optimizing a laser system. Compared to scanning slit beam profilers, camera beam profilers can capture

| Item # | BC106N-UV(/M) | BC106N-VIS(/M) | | | |
|--------------------------|--|-------------------------|--|--|--|
| Wavelength Range | 190 - 350 nm ^a | 350 - 1100 nm | | | |
| Power Range | 50 fW - 1 W ^b | 1 fW - 1 W ^c | | | |
| Beam Diameter | 30 µm - 6.6 mm | | | | |
| Compatible Light Sources | CW, Pulsed ^d | | | | |
| Pulse Frequency | 1 Hz - 50 kHz (Single Pulse Exposure), Unlimited (Multi-Pulse Exposure) | | | | |

- · Design range of Lumigen coating, sensitivity is given throughout 1100 nm but shows increased non-uniformity and noise compared to uncoated BC106N-VIS.
- @ 200 nm, depending on Beam Diameter & ND Filter. See Specs and ND Filter tabs for details.
- @ 550 nm, depending on Beam Diameter & ND Filter. See Specs and ND Filter tabs for details.
- · Damage threshold data is currently not available for our beam profilers. For use with pulsed lasers, we recommend the following procedure as a guideline for determining a safe upper limit: Set the beam profiler to the maximum integration time (i.e., set the exposure to 1 s). Slowly increase the power until your signal reaches approximately 50% of the intensity as shown in the Profile window of the Beam software package. Multiply this power by a factor of 10. This is the safe upper limit of the mean pulse power for the beam profiler.

a more detailed beam profile and provide a true 2D analysis of the beam's power density distribution.

These beam profilers are suited for use with either continuous wave or pulsed sources. Several trigger modes allow flexible capturing of single pulses, including a TTL input for triggered single pulse detection of signals with a repetition rate lower than 50 kHz. In non-trigger mode, pulses with repetition rates above 50 kHz will be seen as a continuous wave source by the beam profiler.



Each beam profiler contains a high-quality 12-bit CCD camera with an active sensor size of 8.77 mm x 6.6 mm, a resolution of 1.4 Megapixels, and a 20 µs minimum exposure time. Compared to CMOS profilers, the high-quality CCD camera offers excellent sensitivity and low noise and enhanced global shutter efficiency for improved exposure accuracy and uniformity. The automatic dark level calibration provides very stable dark currents independent of the device settings, eliminating the need to recalibrate the dark level for each user setting.

Click to Enlarge Front View of the BC106N-UV Beam Profiler

An integrated filter wheel with 6 high-quality neutral density (ND) filters allows the profiler to be adapted for use with beam intensities from femtowatts to 1 W (see the *Specs* and *ND Filter* tabs for details). Each filter housing is internally SM05 (0.535"-40) threaded for easy integration with Thorlabs' lens tube systems and mounts for other optical components such as additional attenuation filters. An 8-

32 (M4) tap on the side of the beam profiler housing and 8-32 (M4) and 1/4"-20 (M6) taps on the bottom of the housing allow for two different mounting orientations.

The integrated power meter can be user calibrated and is perfectly suited for simultaneous power and beam shape optimization without the need for an external power meter. A measured mean value of the ambient light intensity is subtracted from the beam profile measurement so as to compensate for ambient light. The automatic exposure and gain control feature adapts the camera settings to the actual beam intensity. The USB 2.0 interface allows up to 10 full frames per second at full resolution. Measurements at higher frame rates can be achieved and transferred with reduced frame sizes.

The BC106N Beam Profilers are shipped with Thorlabs' Beam software package. Features of the software package are listed under the *User Interface* tab. Thorlabs' Beam software can be downloaded via the links on the *Software* tab, along with programming reference guides for LabVIEW[™], Visual C++, Visual C#, and Visual Basic.

Extension sets are available below to convert these camera beam profilers into a fully-automated M^2 measurement system. Thorlabs also offers a scanning slit beam profiler, as well as a complete M^2 analysis systems with the beam profiler included.

SPECS

| Item # | BC106N-UV(/M) | BC106N-VIS(/M) | BC106N-UV Operating Ranges (200 nm) |
|------------------------------------|--|---|--|
| Wavelength Range | 190 - 350 nm ^a | 350 - 1100 nm | 10° |
| Power Range | 50 fW - 1 W ^b | 1 fW - 1 W ^c | |
| Beam Diameter | 30 µm - | 6.6 mm | |
| Compatible Light Sources | CW, P | lulsed ^d | 10 ⁴⁰ 10 ⁴⁴ 10 ⁴⁴ 10 ⁴⁴ |
| Pulse Frequency | 1 Hz - 50 kHz (Sing Unlimited (Multi- | · · · · · · · | 10 ⁻¹⁸ |
| Absorptive Neutral Density Filters | | Minimum Limit Mazimum Limit Withoutan ND Filter Withoutan ND Filter With a 40 dB ND Filter | |
| Nominal Values | 20 dB, 30 dB, 40 dB | 20 dB, 40 dB, 60 dB The neu (Two Sets) ^e damag | Click to Enlarge tral density filter will begin to heat up and can be ed if exposed to incident powers above 1 W for |
| AR Coating Wavelength Range | 070 700 f | 350 - 700 nm (Three Filters) | more than a few seconds. |
| An coating wavelength hange | 350 - 700 nm ^f | 650 - 1050 nm (Three Filters) | BC106N-VIS Operating Ranges (550 nm) |
| Reflective Neutral Density Filters | | S | 10° |
| Nominal Values | 20 dB, 30 dB, 40 dB | N/A N/A | 10 ⁴ |
| AR Coating (Back Side of Filter) | 220 to 240 nm ^g | N/A | |
| Sensor | | | |
| Coating | Lumigen ^a | None | 10 ⁻¹⁰ 10 ⁻¹⁰ 10 100 1000 Beam Diameter (μm) |
| Chin | 2/3" Sony EXvie | ew HAD™ CCD | Minimum Limit Maximum Limit |
| Chip | Sensor ICX285/ | AL, Windowless | Without an ND Filter Without an ND Filter |
| Aperture Size (Max) | 8.77 mm | i ne neu | Click to Enlarge tral density filter will begin to heat up and can be |
| Pixel Size | 6.45 μm > | domoor | ed if exposed to incident powers above 1 W for more than a few seconds. |
| Resolution (Max) | 1360 x 1024 pixel | ls, ROI Selectable | |

| | | Relative Response |
|---|---|---|
| Camera | | |
| Shutter | Global | 8 1.0 8 0.8 8 0.8 |
| Max. Frame Rate @ Full Resolution | 10 fps ^h | |
| Frame Rate @ 640 x 480 | >27 fps ^h | 2 0.4 |
| Frame Rate @ 320 x 240 | >43 fps ^h | |
| Image Digitization | 8 bit (0 - 255 Digits) or 12 bit (0 - 4095 Digits) | 200 300 400 500 500 700 800 900 1000 1100 Wavelength (nm) Click to Enlarge |
| Signal-to-Noise Ratio | ≥62 dB | The graph above shows the relative reponse curves of the BC106N-VIS and the BC106N-UV without the use of |
| Exposure Range | 20 µs - 1 s | an ND filter. The blue-shaded region marks the specified operating wavelength range for the BC106N-UV, while |
| Gain Range | 1x - 16x | the while shaded region is this range for the BC106N- VIS. The Lumigen coating on the CCD in the BC106N-UV |
| Image Capture Modes | Single Frame, Continuous, Hardware Triggered | increases the chip response at lower wavelengths, at the |
| Sensor Distance to Front Filter HolderSurface ⁱ | 14.0 mm (0.55") | expense of sensitivity at visible wavelengths. |
| Interfaces | | |
| Trigger Input | TTL Level , BNC Jack | |
| Trigger Delay | 42 μs - 1 s, Programmable | |
| PC Interface | High Speed USB 2.0 | |
| General | | |
| Operating Temperature | 5 to 35 °C | |
| Storage Temperature | -40 to 70 °C | |
| Physical Size (H x W x D) | 80 mm x 80 mm x 36.5 mm Including Base Plate, Filter Wheel and Filters | |
| Weight | 310 g | |
| Mounting | 1/4"-20 (M6) and 8-32 (M4) Taps on Bottom, 8-32 (M4) Tap on Side | |
| Power Supply | 2.4 W, USB Bus Powered | |
| Safety | CE Compliant | |

• Design range of Lumigen coating, sensitivity is given throughout 1100 nm but shows increased non-uniformity and noise compared to uncoated BC106N-VIS. Wavelength range of supplied UV ND filters start at 220 nm.

- @ 200 nm, depending on Beam Diameter and ND Filter.
- @ 550 nm, depending on Beam Diameter and ND Filter.
- Damage threshold data is currently not available for our beam profilers. For use with pulsed lasers, we recommend the following procedure as a guideline for determining a safe upper limit: Set the beam profiler to the maximum integration time (i.e., set the exposure to 1 s). Slowly increase the power until your signal reaches approximately 50% of the intensity as shown in the Profile window of the Beam software package. Multiply this power by a factor of 10. This is the safe upper limit of the mean pulse power for the beam profiler.
- One set of filters is AR coated for the 350 nm to 700 nm range while the other is AR coated for the 650 nm to the 1050 nm range. See the *ND Filters* tab for more information and coating curves.
- These filters are provided for use near the 350 nm upper wavelength range of the BC106N-UV(/M). See the *ND Filters* tab for more information.
- The AR-coating on the non-reflective side of these filters provides <0.25% average reflectivity over this specified wavelength range. The filter still provides attenuation outside of this region (as shown on the *ND Filters* tab), but the the AR coating will not perform as well.
- Highly dependent on PC processor and graphic adapter performance.
- Please click here for a detailed drawing that shows the distance between the sensor position and the various edges of the beam profiler's housing.

All technical data are valid at 25 \pm 5 °C and 45 \pm 15% relative humidity.

ND FILTERS

Neutral Density Filters

Six neutral density (ND) filters are included with each CCD camera beam profiler. The absportive ND filters have antireflection (AR) coatings on both sides,

while the reflective ND filters that come with the BC106N-UV have an AR coating on their non-reflective surface. This feature, combined with a 30 arcminute wedge, reduces artifacts in the measured beam profile that result from internal reflections in the filter. The plots below show the filter attenuation curves in dB. The equivalent % transmission is provided in the raw data file for each filter set.

BC106N-UV(/M)

The BC106N-UV comes with six neutral density filters, three of which are absorptive and three are reflective. The three reflective ND filters have an AR coating for the 220 to 340 nm range on their nonreflective surface. Since the BC106N-UV's camera is also sensitive to short wavelength visible light (see the relative response curve on the Specs tab), three absorptive ND filters with an AR coating on both sides are included for use near the 350 nm upper limit of the specified wavelength range.

BC106N-VIS(/M)

The BC106N-VIS comes with six absorptive ND filters. The filters have an AR coating deposited on both sides, with one set coated for the 350 nm to 700 nm range and the other coated for the 650 to 1050 nm range.

| | ND Filters Included with BC106N-UV(/M) | | | | | | | |
|---|--|-------------------------------|------------|------------|-------------------------------|----------|------------------|--|
| | Туре | | Reflective | Absorptive | | | | |
| è | AR Coating Wavelength Range | 220 nm to 340 nm ^a | | | 350 nm to 700 nm ^b | | | |
| | Nominal Filter Attenuation | 20 dB | 30 dB | 40 dB | 20 dB | 30 dB | 40 dB | |
| | Item # | NDUV520B | NDUV530B | NDUV540B | NE520B-A | NE530B-A | N/A ^c | |
| | Filter Wheel Position | 1 | 2 | 3 | 4 | 5 | 6 | |

- The AR-coating on the non-reflective side of these filters provides <0.25% average reflectivity over this specified wavelength range. The filter still provides attenuation outside of this region (as shown in the plot below), but the the AR coating will not perform as well.
- This is the specified wavelength range for optimum performance of the AR coating. These filters are included for
 use near the upper limit of the BC106N-UV's wavelength range, since the camera is also sensitive to short
 wavelength visible light. The filter still provides attenuation outside of this region (as shown in the plot below), but
 the the AR performance is not specified over this range.
- This filter is not available separately.

| | ND Filters Included with BC106N-VIS(/M) | | | | | | | |
|---|---|------------------|------------------|----------|-------------------|------------------|----------|--|
| | Туре | | Absorptive | e | Absorptive | | | |
| | AR Coating Wavelength Range | 350 nm to 700 nm | | | 650 nm to 1050 nm | | | |
| - | Nominal Filter Attenuation | 20 dB | 40 dB | 60 dB | 20 dB | 40 dB | 60 dB | |
| | Item # | NE520B-A | N/A ^a | NE560B-A | NE520B-B | N/A ^a | NE560B-B | |
| | Filter Wheel Position | 1 | 2 | 3 | 4 | 5 | 6 | |

· These filters are not available separately.



The graph above shows the filter attenuation with respect to wavelength for the six filters included with the BC106N-UV. The absorptive filters are recommended for use near the 350 nm upper limit of the BC106N-UV's operating wavelength range.



The graph above provides an example of the performance of the AR coating applied the reflective ND filters that are included with the BC106N-UV(/M). The coating is designed to provide less than 0.25% average reflectance over the blue-shaded region.



BC106N-VIS Filter Attenuation

The graph above shows the filter attenuation with respect to wavelength for the six filters included with the BC106N-VIS.



The graph above provides an example of the performance of the AR coating applied to three of the filters that are included with the BC106N-VIS(/M) and the absorptive ND filters included with the BC106N-UV(/M). The coating is designed to provide less than 0.5% average reflectance over the designated coating range. More information on the coating performance may be found here.



PIN DIAGRAMS



Do not exceed -0.5 V ... +6.5 V. Input Impedence > 100 k Ω

USER INTERFACE

Thorlabs Beam Software for the **BC106N Beam Profilers**

- · GUI with Adjustable Layout: Windows with Different Measurement Results can be Rearranged and Resized within the Workspace
- · 2D and 3D Views of the Beam Profile
 - Selectable Overlays such as Peak, Centroid, and Cut Profiles
 - 3D View is Fully Rotatable
- M² and Divergence Measurements Compliant with ISO 11146
- Data Export:
 - · Results can be Exported from Windows in **Different Formats**
 - Sequential Saving
- · Pass/Fail Tests with Customizable, Lockable and Saveable Pass/Fail Parameters
- Power Correction Available for Absolute Power Measurements
- Supports TSP01 for Temperature Logging During Long-Term Measurements

Main Window



Click to Enlarge

The main window of the GUI includes the menu bar, tool bar, status bar, and a frame where several windows can be displayed. This version of the Main Window includes several panels: Beam Settings, Calculation Results, 2D Projection, and 3D Profile. The Beam Settings Panel displays all important information in a single location; this panel can be unpinned from the main window and moved to a second location, such as another monitor.

Thorlabs' Camera Beam Profilers, Scanning Slit Beam Profilers, and M² Measurement Systems all use the Thorlabs Beam software package. The screenshots below highlight key features and measurement modes that can be used with our camera beam profilers, including 2D projections of the beam profile and

measurement of the beam stability and position. If an M² Extension Set (available below) is added to the system, the software also enables M² and beam divergence measurements.

The latest version of the Beam software package can be downloaded from the Software tab.



2D Projection of the Beam Profile

Click to Enlarge

The 2D Projection graph shows the image from the Beam Profiler indicating the power intensity distribution within the selected Region of Interest (ROI). Buttons along the side allow users to save the image, show or hide the x and y scales, mark the centroid or peak positions, and display an approximated Beam Ellipse superimposed on the image.

Calculation Results

| | | storefor f | and the | | | | - 80 |
|-------|--|------------|---------|---------|--------------|-------------|------------|
| 1 | Parameter | Value | Unit | Tost | | Hin. | Nax. |
| | Calculations Derived from Raw Dat | sa . | | | | | |
| | Represivents (4 Signal) X | 2083.33 | um. | Date | ×. | 2900.03 | 3100.00 |
| | Beam Weth (4 Stone) Y | 1022.07 | um. | Pasa | v | 2900.03 | 3100.00 |
| | Beam Dameter (4 Stand) | 2010.45 | um. | | | 2900.00 | 3100.00 |
| | Peek Pusitor X | -19.53 | Las. | | | 0.00 | 0.00 |
| | Peak Position Y | 53.58 | pro- | | | 0.00 | 0.00 |
| · · · | Cartolic Position X (Balarance Position) | 0.00 | um . | | 10 | 0.00 | 0.00 |
| | Central Position Y | 0.00 | pm . | | | 0.00 | 0.00 |
| | AD Saturation | 80.71 | 50 | 19355 | 2 | E0.03 | 95.00 \$ |
| | Total Power | 0.36 | mill | 🐨 Fail | ×. | 0.50 0 1 | 0.75 3 |
| | Ellipse (fitted) | | | | | | |
| | Elutoty | 59.44 | 3. | P.455 | 14 | 65.03 CV | 100.00 % |
| | Minor Ellipse Dismeter (13.5%) | 2718.25 | yes. | Dass | ¥. | 2600.03 2 4 | 2500.00 -5 |
| 181 | Major Filippa Discrator (15.5%) | 2731.40 | per la | Date | \mathbf{x} | 2000.03 014 | 2000.00 |
| | Eccertricty | 10.55 | 55 | | | 0.00 | 0.00 |
| | Ononfation | | dog | | | 0.00 | 0.00 |
| | Profile Measurement | | | | | | |
| | Beam Webb Clip X (18,5%) | 2009.34 | um. | Plass | 1 | 2600.03 | 2000.00 |
| | Eesth Width Clip Y (13,5%) | 2899.78 | Las . | Pass | ×. | 2600.03 | 2800.00 1 |
| | Fit Measurement | | | | | | |
| | Georgen Intersity X | \$7.37 | 5. | | | 0.00 | 0.00 |
| | Gaussian Intensity Y | 56 58 | 45 | | | 0.00 | 0.00 |
| | Goussian Diameter X | \$527.47 | um. | | | 0.00 | 0.00 |
| | Ooussian Diameter Y | 2000.24 | um. | | | 0.00 | 0.00 |
| | Bessel Intensity X | 58.00 | % | | | 0.00 | 0.00 |
| | Elessed Interactly Y | W2.82 | 9. | | | 0.00 | 0.00 |
| | Environment Parameter | | | | | | |
| | Cartera Temperature | 24.25 | *C | A Diff. | × | 22.03 214 | 21.00 -5 |



The Calculation Results window displays the results of calculations performed by the software, including beam width, centroid and peak positions, power, ellipticity, and fits of the beam profile. This panel also includes a Pass/Fail test. For each parameter, a minimum or maximum can be set as criteria. After the calculations are complete, the user can save them in .txt, csv, or .xls format. In addition to saving single measurement results, diagrams, and device data, the software can automatically sequentially save this information for a series of measurements.



Beam Stability

Click to Enlarge

The Beam Stability Window allows the stability versus time to be recorded and viewed. Display options include the Centroid Positions, Latest Plotted Centroid, Rolling Centroid Positions, Reference Positions, and Smallest Enclosing Circle.

Plot Centroid and Peak Positions





Mile Octor Carling Mile Mile

M² Measurements

Click to Enlarge

The beam diameter and location of the beam waist are shown after an M² analysis has been performed. Note: This functionality is only enabled when one of the M² analysis systems is connected to the PC.

Divergence Measurements



Click to Enlarge The divergence of the beam is shown after an M² analysis has been performed. Note: This functionality is only enabled when one of the M² analysis systems is connected to the PC.

SOFTWARE

Software Packages for Thorlabs' Beam

System Requirements

1

Profilers

The Beam software package can be downloaded by clicking on the Software button below. The software download page also offers programming reference notes for interfacing with our beam profilers using LabVIEW[™], Visual C++, Visual C#, and Visual Basic. Please see the *Programming Reference* tab on the software download page for more information and download links.

Features

- Settings Panel Displays All Important
 Parameters in a Central Location
- Customizable Calculation Results
 - Measured Parameters can be Individually Hidden
 - Adjustable Row Heights
 - Enhanced Beam Stability Window Measures and Displays the Smallest Enclosing Circle Around the Centroid Point Cloud
- Alignment Wizard to Aid in Correctly Aligning the M2MS M² Measurement Systems
- Language Settings of English, German, or Chinese

Software

Version 7.1.4871.269 (June 21, 2021)

Standard full version of software package for 32-bit and 64-bit Windows with driver and graphical user interface for operating the device in standard applications.



SHIPPING LIST

| Item # | Beam Profiler | Filter Wheel with Neutral Density Filters | Accessories | |
|--------------------|---|---|-------------------------------------|--|
| BC106N- UV(/M) | Camera Beam Profiler for 190 - 350 nm | Reflective ND Filters (240 nm - 350 nm AR Coating on Back Surface): 20 dB, 30 dB, 40 dB Absorptive ND Filters with Coating for 350 - 700 nm: ^a 20 dB, 30 dB, 40 dB | A to Mini B USB 2.0 Cable, 3.0 m | |
| BC106N- VIS(/M) | Camera Beam Profiler for 350 - 1100 nm | Absorptive ND Filters with Coating for 350 - 700 nm: 20 dB, 40 dB, 60 dB Absorptive ND Filters with Coating for 650 - 1050 nm: 20 dB, 40 dB, 60 dB | Quick Start Guide | |

• These filters are provided for use near the 350 nm upper wavelength range of the BC106N-UV(/M); they are not designed for UV wavelengths.

| Operating System | | Windows [®] 7 (32 Bit), 7 x64 Edition (64 Bit) 8.1 (32 Bit), 8.1 x64 Edition (64 Bit), 10 (32 Bit), or 10 x64 Edition (64 Bit) | | |
|----------------------|-------------|---|--|--|
| Connectivity | | USB 2.0 High Speed Port | | |
| Monitor Resolution | | 1024 x 758 Pixel (Min), ≥16 Bit Color Depth | | |
| Processor (CPU) | Minimum | Pentium 4 (2.6 GHz Min), Intel or A64 3000+ AMD (3.0 GHz Min) | | |
| | Recommended | Intel Core 2 i5 or AMD Ryzen 5 (3.0 GHz Min) | | |
| Memory (RAM) Minimum | | 4.0 GB RAM | | |
| Memory (RAM) | Recommended | 8.0 GB RAM | | |
| | Required | OpenGL (Specification GLX 1.3 Up) | | |
| Graphics Adapter | Minimum | Radeon: X100 Series ≥X850, X1000 Series ≥X1600, HD Series ≥2400; Geforce: 7 Series ≥7600, 8 Series ≥8500, 9 Series ≥9600; Quadro: FX Series ≥FX770M | | |
| | Recommended | Radeon: HD Series ≥7000; Geforce: GTX Series ≥500; | | |

Geforce: GTX Series ≥500;

Part Number

CCD Camera Beam Profiler

| BC106N-UV/M | CCD Camera Beam Profiler, Ø30 µm - 6.6 mm, UV, 190 - 350 nm, Metric | \$4,924.72 | Lead Time |
|--------------|---|------------|-----------|
| BC106N-VIS/M | CCD Camera Beam Profiler, Ø30 µm - 6.6 mm, VIS, 350 - 1100 nm, Metric | \$4,647.70 | Lead Time |
| BC106N-UV | CCD Camera Beam Profiler, Ø30 µm - 6.6 mm, 190 - 350 nm | \$4,924.72 | Lead Time |
| BC106N-VIS | CCD Camera Beam Profiler, Ø30 µm - 6.6 mm, 350 - 1100 nm | \$4,647.70 | Lead Time |

M² Measurement Extension Sets

- Combine with BC106N Scanning Slit Beam Profilers to Build
 - Complete M² Measurement System
- Mirrors for the 250 600 nm or 400 2700 nm Range
- Mounting Adapters for BC106N Camera and BP209 Scanning Slit Beam Profilers
- Includes an Alignment Laser

These extension sets are designed to convert Thorlabs' Camera or Scanning Slit Beam Profilers into a fully automated, motorized M² measurement system. The M2MS has internal mirrors for wavelengths between 400 - 2700 nm and the M2MS-AL has internal mirrors for wavelengths between 250 - 600 nm. A magnetic mount at the input port allows the included AR-coated lenses (see boxes below) to be easily switched out to optimize the system for your laser source.

The beam profiler and focusing lens remain in a fixed position. For ${\rm M}^2$ measurements, the beam path length is varied using a movable retroreflector mounted on a previous-generation DDSM100/M translation stage, which has a translation range of 100 mm and a maximum velocity of 500 mm/s.

The side of the M² measurement system features an integrated USB 2.0 hub, which has ports for the beam profiler, one other device such as the TSP01 USB temperature and humidity controller, and a mini USB output connection to a PC. The translation stage inside of the system also communicates with the computer through this hub. The system is controlled via the Thorlabs Beam software package, which is also use to control our beam profilers (see the *Software* tab), which enables accurate measurements of a variety of beam-related parameters.

The housing of the M^2 measurement rests on four feet at the corners created by a 0.5 mm deep relief cut in the base. A set of RDF1 rubber damping feet are included. Five M6 taps allow for the installion of four damping feet with one near each corner or in a configuration using three damping feet.

More information about these complete M^2 measurement systems, as well information about M^2 measurement systems that incorporate our CCD camera beam profilers can be found here.

Lenses Included with M2MS-AL*

Lenses with f = 250 mm Mounted in CXY1QF Quick Release Plate:

- LA4158-UV (AR Coated for 245 400 nm)
- LA1461-A (AR Coated for 350 700 nm)

*Additional lenses for shorter UV wavelengths and the CXY1QF quick release front plate are available separately to enable further customization of the M² measurement system.

M2MS M2MS-AL Item # Wavelength Range 400 - 2700 nm^a 250 - 600 nm^a BC106N-VIS(/M) BP209-VIS(/M) BC106N-UV(/M) Beam Profiler Compatibility^b BP209-IR(/M) BP209-VIS(/M) BP209-IR2(/M) Translation Stage DDSM100/M^c Travel Range 100 mm Velocity (Max) 500 mm/s 200 mm (Total) Effective Translation Range ±100 mm (from Focal Point) 250 mm Lens Focal Length 70 mm **Optical Axis Height** (Without Additional Feet) >1.0 (No Upper Limit) M² Measurement Range +5% Typical M² Accuracy (Depends on Optics and Alignment) Minimum Detectable Divergence < 0.1 mrad Angle Applicable Light Sources CW. Pulsed^a 15 - 30 s Typical Measurement Time (Depends on Beam Shape and Settings) **General Specifications** 300 mm x 175 mm x 109 mm Size (Without Beam Profiler) 4.2 kg Weight (Without Beam Profiler)

- · Depending on the beam profiler used with the system.
- The BP10x previous-generation beam profilers are compatible with the M2MS.
- This previous-generation item is not available for individual purchase.

Lenses with f = 250 mm Mounted in CXY1QF Quick Release Plate:

Lenses Included with M2MS*

- LA1461-A (AR Coated for 350 700 nm)
- LA1461-B (AR Coated for 650 1050 nm)
- LA1461-C (AR Coated for 1050 1700 nm)
- LA5255-D (AR Coated for 1650 3000 nm)

*Additional lenses for longer IR wavelengths and the CXY1QF quick release front plate are available separately to enable further customization of the M2 measurement system.

Accessories Included with M2MS-AL and M2MS

- Alignment Laser
- USB 2.0 to Mini B Cable, 3 m
- USB 2.0 to Mini B (Angled), 0.5 m)
 4 Rail Clamps
- 15 V, 3.0 A Power Supply
- 0.05" Hex Key 3 mm Balldriver
- 6 M4 Cap Screws

| Part Number | Description | | Availability |
|-------------|--|------------|--------------|
| M2MS | M ² Measurement System Extension Set, 400 - 2700 nm | \$6,211.35 | Today |
| M2MS-AL | M ² Measurement System Extension Set, 250 - 600 nm | \$6,211.35 | Lead Time |

